# Osai Automation Systems





**NEOKGD**KNOWN GOOD DIES TEST HANDLER



Capable of handling and testing bare dies with a throughput of up to 1,800 UPH (units per hour) including the **Hi-speed** optical inspection systems (5s or 6s).

The bare dies are automatically handled to and from the diced wafer, contacted, and final tested at both **hot and ambient temperatures** (programmable range).

**NeoKGD** is a **standard platform** designed to accommodate the customer's needs through a wide matrix of available options. These options include test requirements, probing technology, and the selection of output and reject segregation media.

Multiple configurations, combined with a **compact footprint** and high throughput, make NeoKGD an effective test handler for reducing production costs of KGD devices and a reliable solution for the most challenging manufacturing needs.

## **KEYPOINTS**

**Input media:** 6", 8" or 12" wafer frame

## Output media:

Re-constructed wafer frame 2", 4" Waffle and Gel Pack Tape & Reel Jedec or Custom Tray form

## Reject media:

BinBoxes

2", 4" Waffle and Gel Pack

Supported Tests: AC, DC, Hi-Pot Test

## **Temperature Control:**

From Ambient up to Hot Temp (175°C) Closed-loop Temperature Control

Accuracy ±2°C (up to 175°C)

Optical Inspection: 5s, 6s, Hi-Speed Capabilities

#### **Probecard Features:**

Automatic Alignment (Probe Needles and Die)
Automatic Cleaning

Embedded Locking System with ATE direct docking capability

## Factory Integration:

SECS/GEM Interface

WaferMapManagement (according to the SEMI standards) Lights-off concept ready (Robotization, AGVs)

## **Equipment KPIs:**

Compact footprint

Overall Equipment Efficiency (OEE): ≥ 92 %

Mean time between failures (MTBF): ≥ 1680 hours

Jam rate: ≤ 1:10k

Conversion time between product/packages ≤ 15 mins

Mean time to assist (MTTA) in Production Mode: less than 3 minutes for hard jam only

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